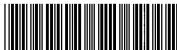


**Search Notes****Application/Control No.**

10/537,372

**Applicant(s)/Patent under  
Reexamination**

DIEM ET AL.

**Examiner**

CHRIS C. CHU

**Art Unit**

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E21.32, 678, 701, 414 & 415	6/22/2008	C.C.
257	417 & 704	6/22/2008	C.C.
257	710 & 723	6/22/2008	C.C.
438	106 & 121	6/22/2008	C.C.
438	125 & 456	6/22/2008	C.C.
438	723	6/22/2008	C.C.
216	2 & 79	6/22/2008	C.C.
73	504.12	6/22/2008	C.C.
73	504.02	6/22/2008	C.C.
73	504.14	6/22/2008	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
As same	as above	6/22/2008	C.C.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB, USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	6/22/2008	C.C.